


<b>Search Notes</b> 	<b>Application/Control No.</b> 10588145	<b>Applicant(s)/Patent Under Reexamination</b> LI, JIAN
	<b>Examiner</b> SHAWNTINA FUQUA	<b>Art Unit</b> 3742

SEARCHED			
Class	Subclass	Date	Examiner
219	392, 385-6, 391-3, 396-8, 414, 430, 432-3	11/21/10	stf

SEARCH NOTES		
Search Notes	Date	Examiner
east text	11/21/10	stf

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--